

*“Accurate infrared spectroscopy determination of interstitial and precipitated oxygen in highly doped Czochralski-grown silicon”.* de Gryse O, Clauws P, Rossou L, van Landuyt J, Vanhellemont J, *The review of scientific instruments* **70**, 3661 (1999).  
<http://doi.org/10.1063/1.1149974>